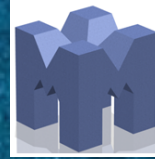




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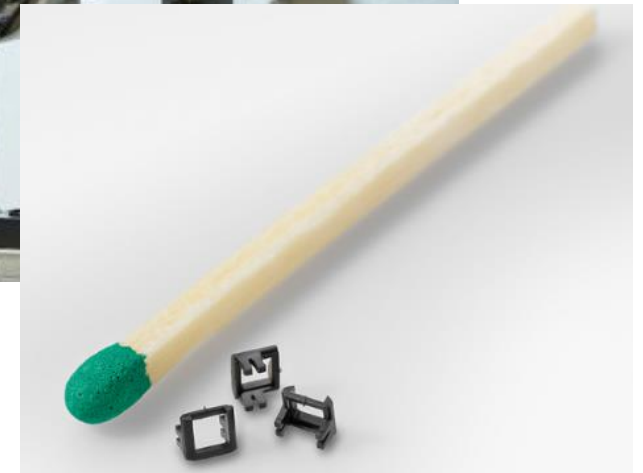
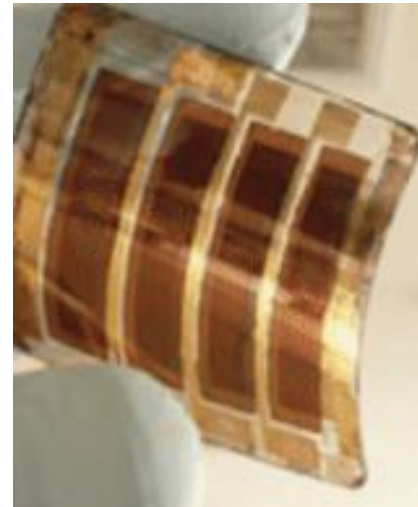
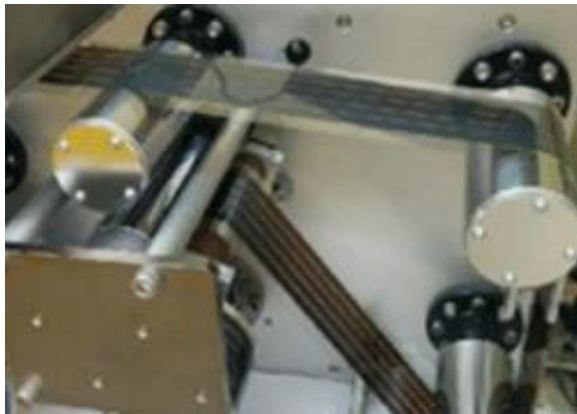
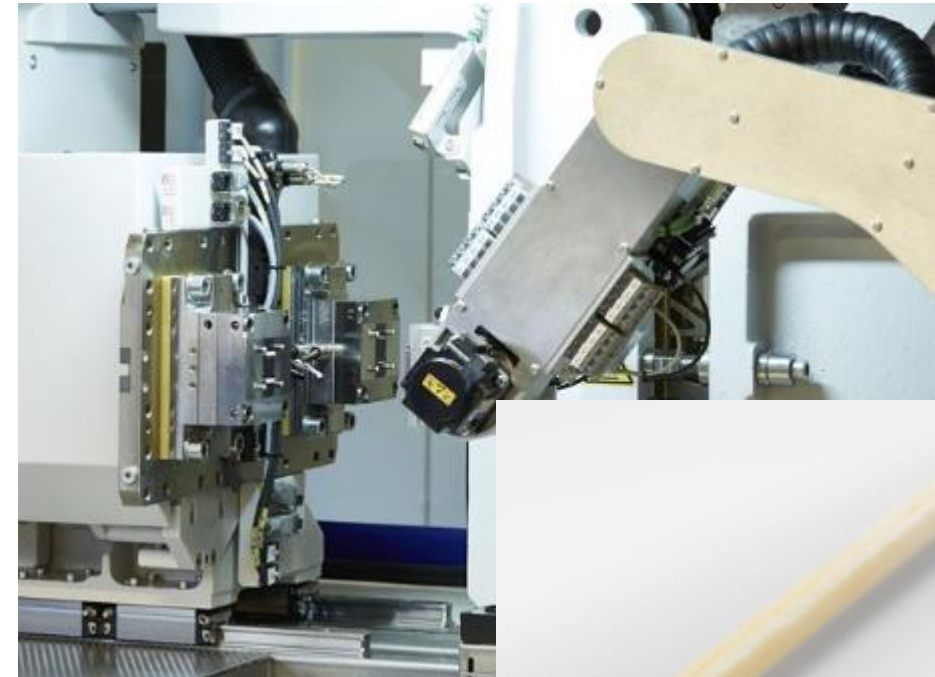
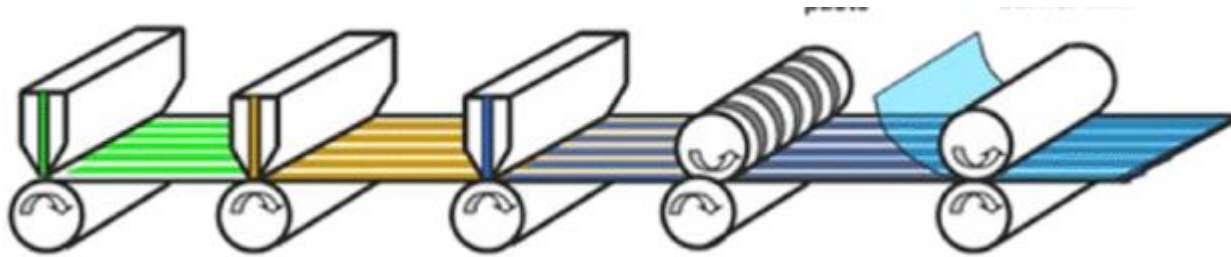


**MANUFACTURING
METROLOGY TEAM**

Methodology for the development of in-line surface measuring instruments (with a case study)

**Wahyudin P. Syam
Manufacturing Metrology Team
Faculty of Engineering**

- Fast and accurate optical in-line measurements for **mass-production** manufacturing processes at millimetre- to micrometre-scale



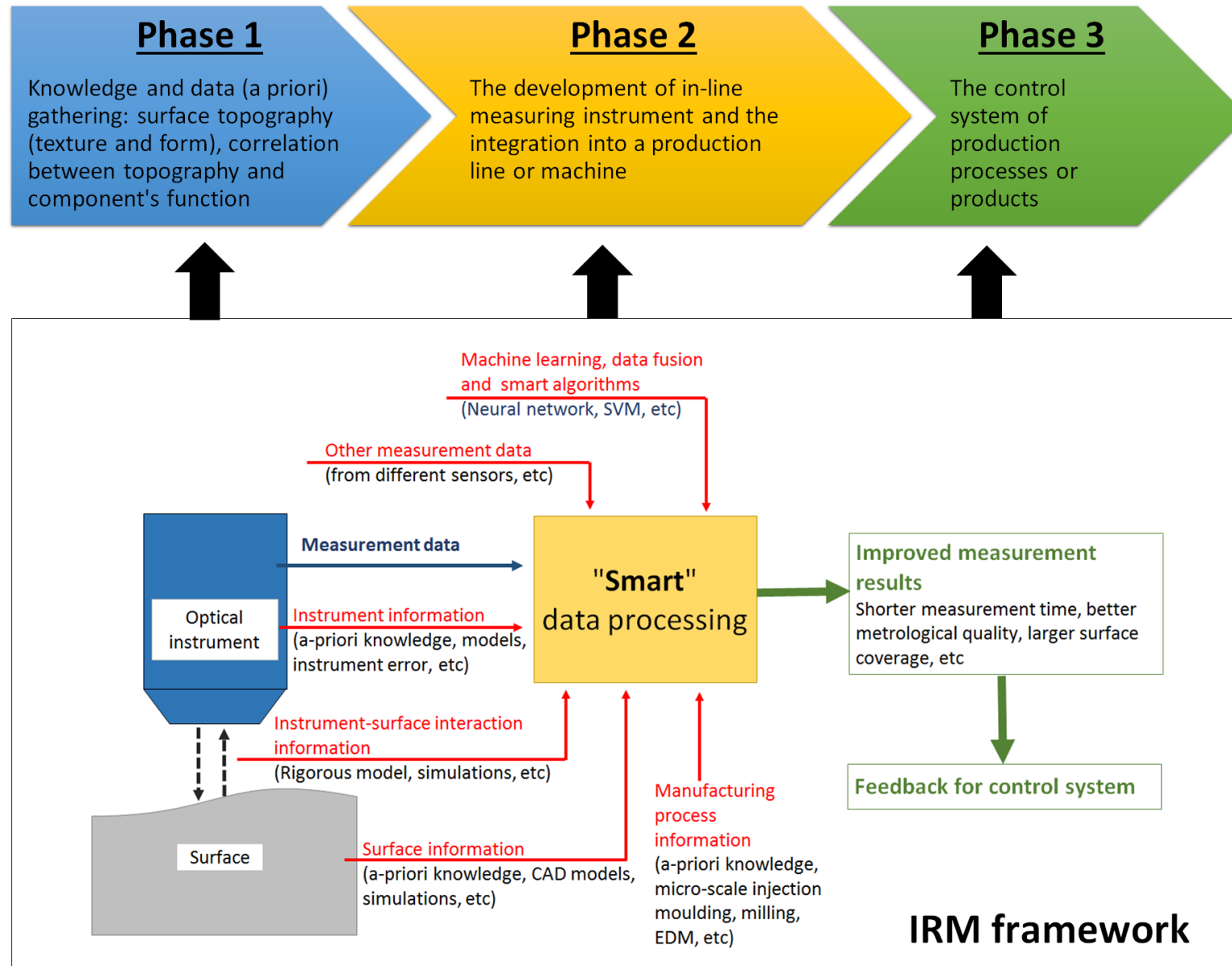
Many challenges for the realisation of fast and accurate optical in-line measuring instruments:

1. Methods
2. Speed
3. System integration and control
4. Traceability
5. Intelligence

NOTE:
Not all challenges
need to be addressed
for a given case



Proposed by
Richard Leach



Rough surface:



PostPro3D machine



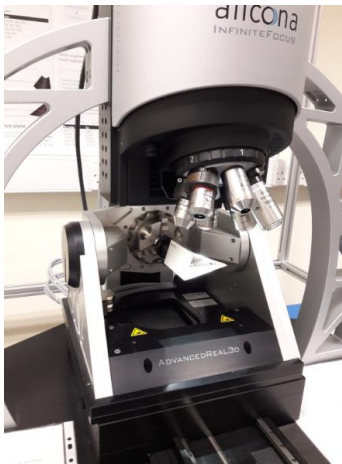
Goal: a fast in-process surface condition detection for close-loop control

Smooth surface:



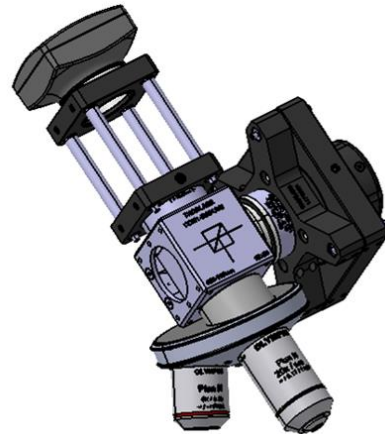
Phase 1

Knowledge and data (a priori) gathering: surface topography (texture and form), correlation between topography and component's function



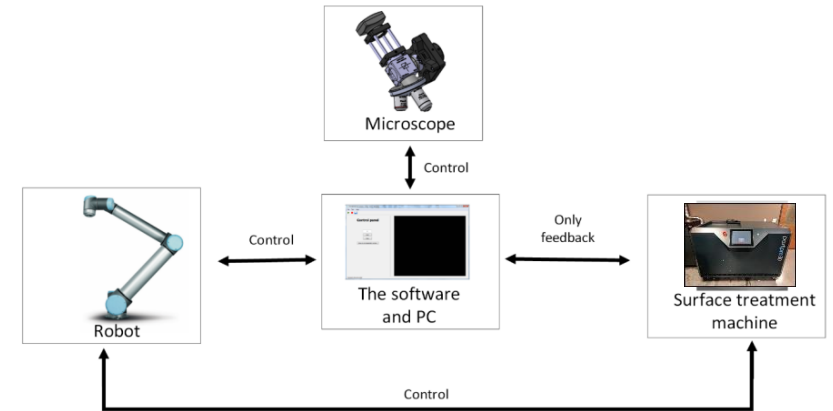
Phase 2

The development of in-line measuring instrument and the integration into a production line or machine

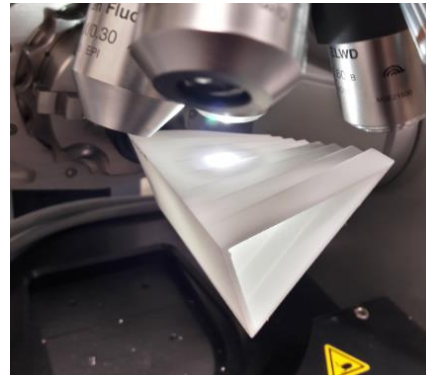
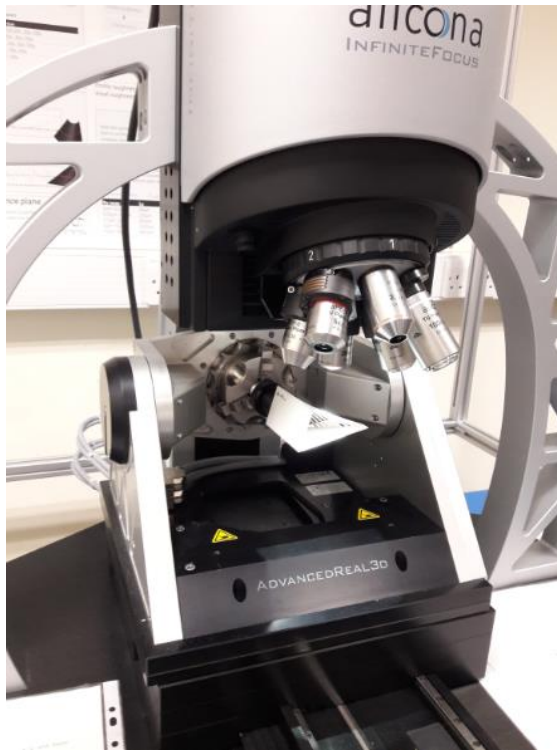


Phase 3

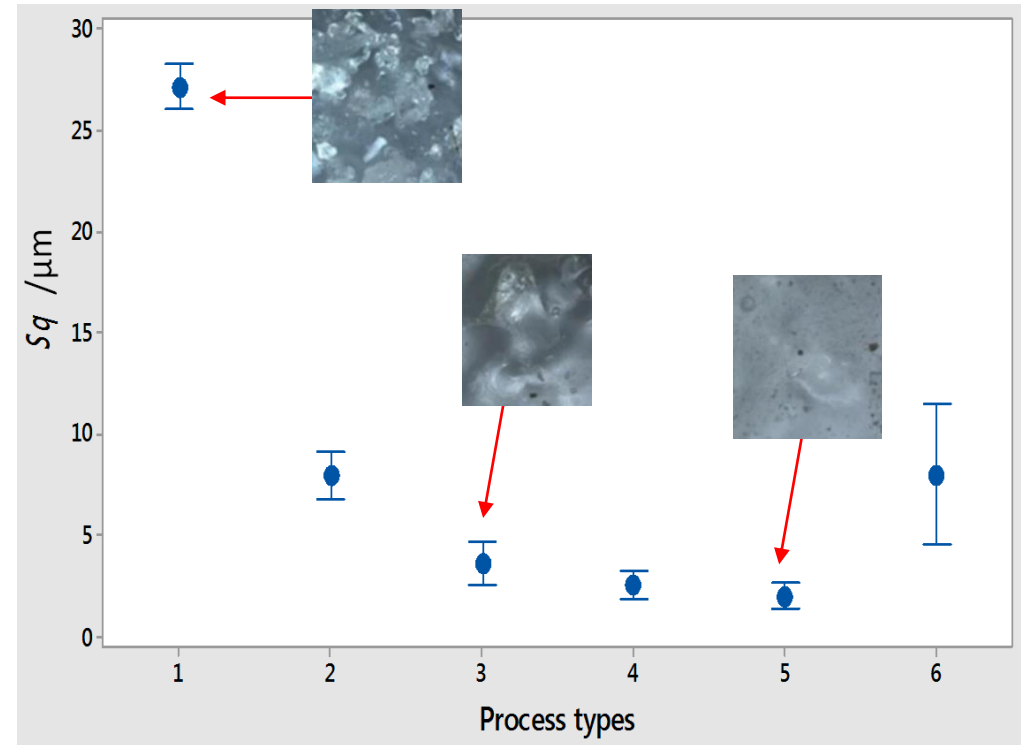
The control system of production processes or products



- A lot of measurements with high resolution focus variation microscopy
- Different polymers measurements
- Understanding surface evolutions during different post processing



1 = 0 %
2 = 25 %
3 = 50 %
4 = 75 %
5 = 100 %
6 = Over process



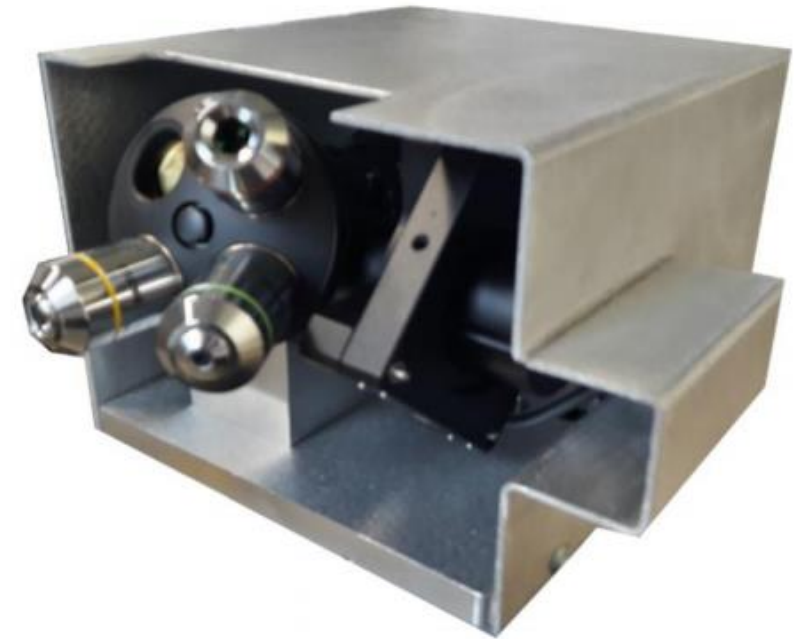
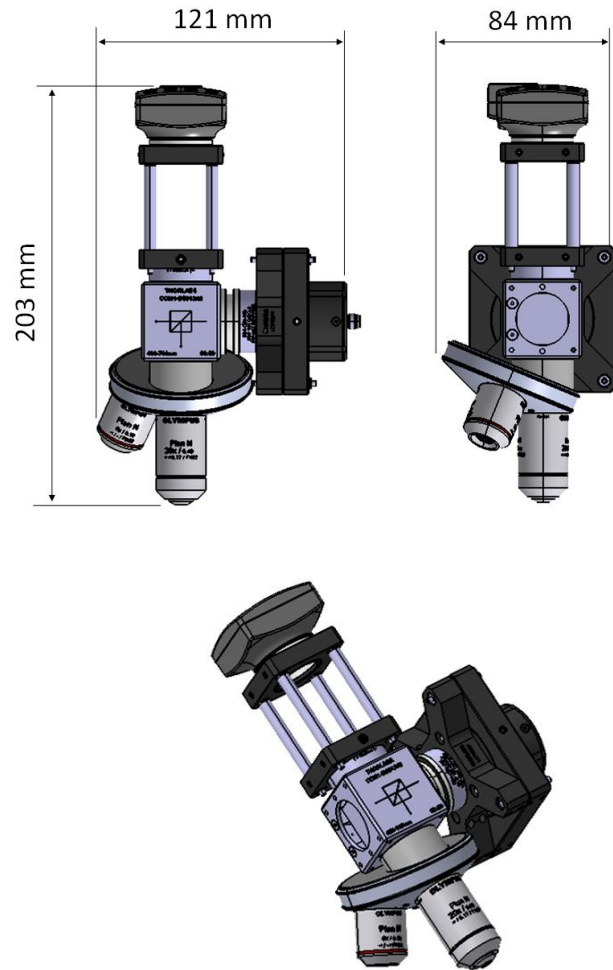
Requirements:

- Small and compact measuring instrument
- Software to control the instrument
- Fast detection of surface condition < 30 s (preferably < 15 s)
- Low cost
- Flexible and portable
- Easy to integrate
- Time limit: a 6 month project

Solution:

- 3D surface reconstruction (at this moment) is not a solution
 - With current technologies, measurements take time = 1 min. (scanning, data processing, etc)
 - High-cost for precision stage (most 3D measuring instruments involve a scanning a surface through its focused position).
 - Longer development time
- 2D image analysis solution is selected
 - Low-cost
 - With machine learning, image analysis is significantly enhanced
 - Absolute surface measurements are not required

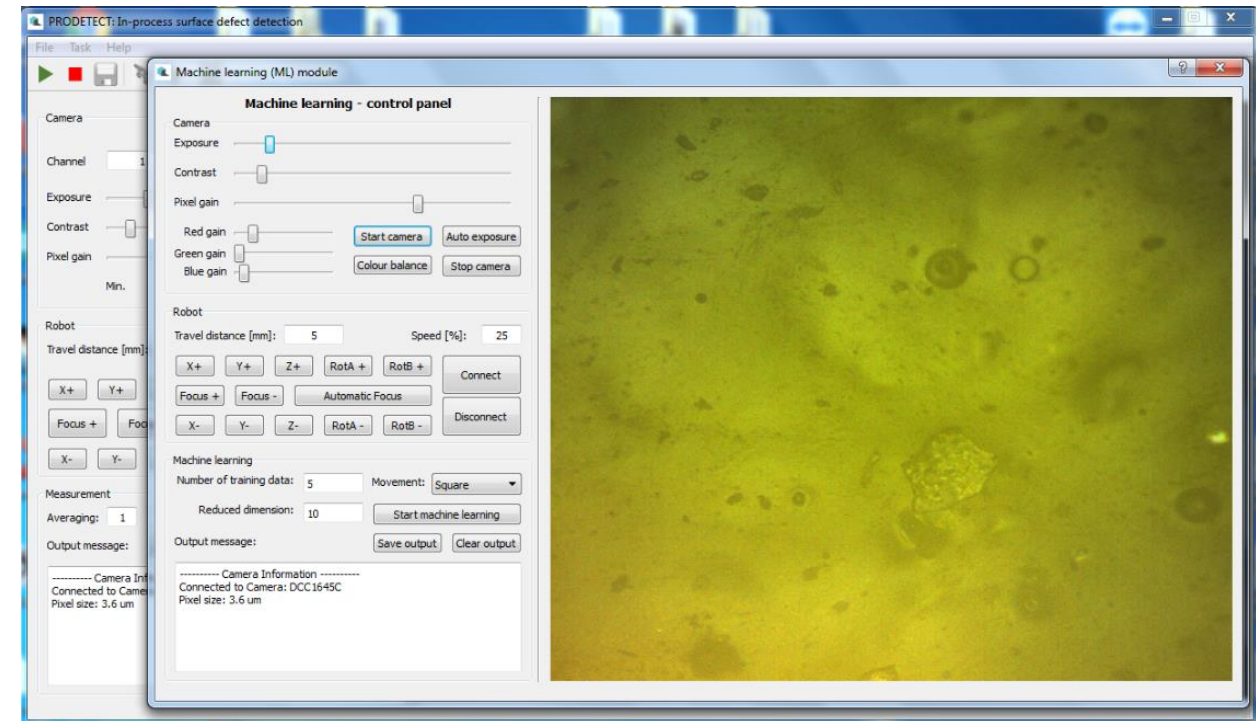
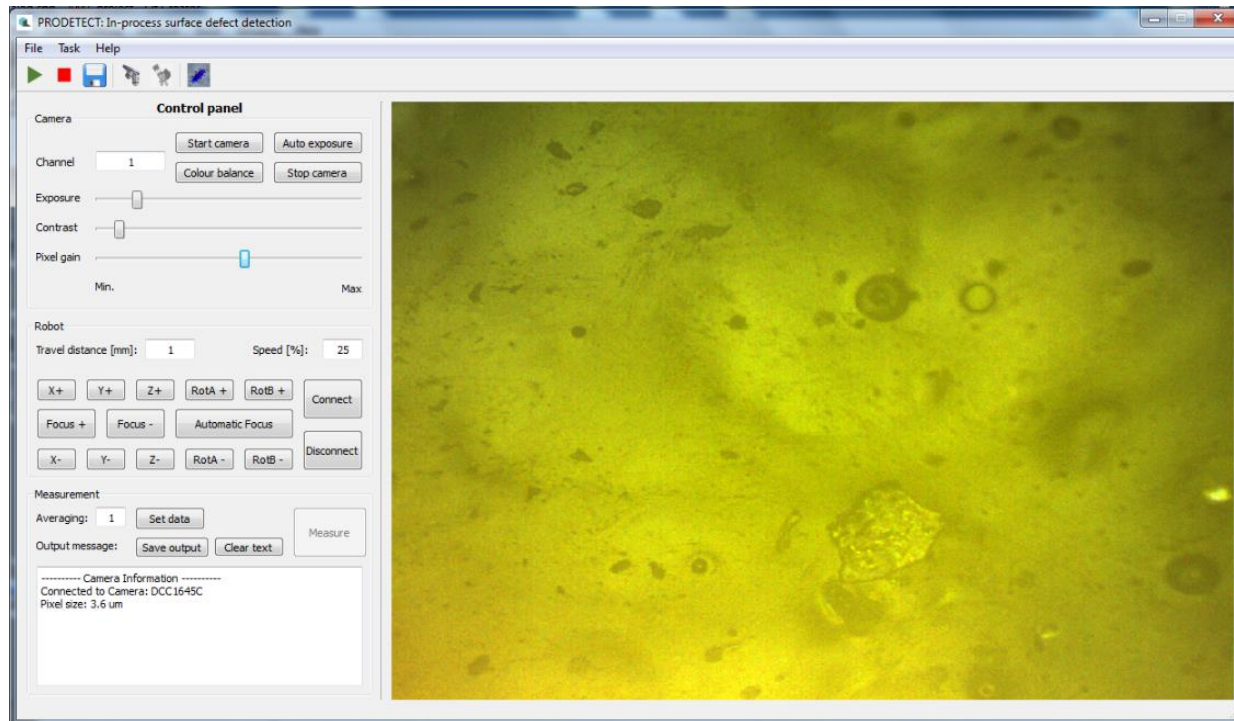
Instrument development:



Software development:

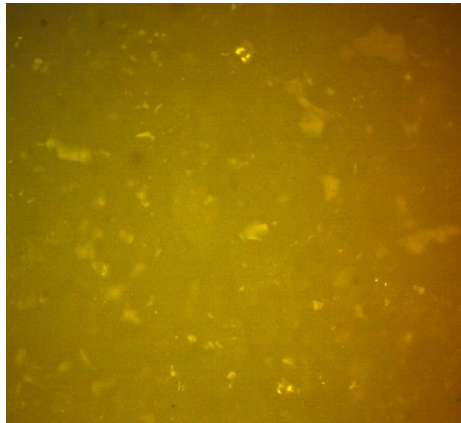
Measurement module

Machine learning module

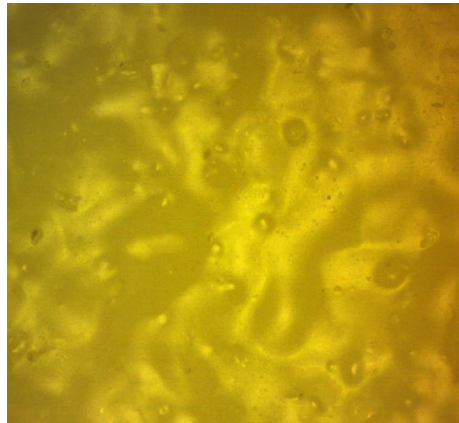


Instrument and software testing: TPU samples

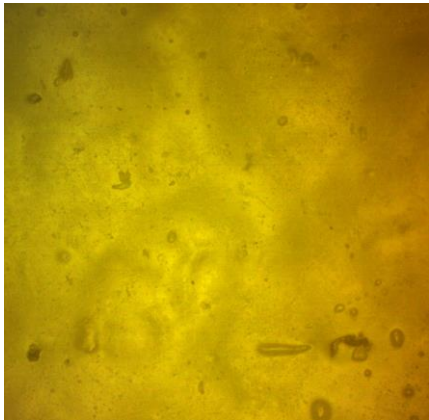
Type 1 – 0 %



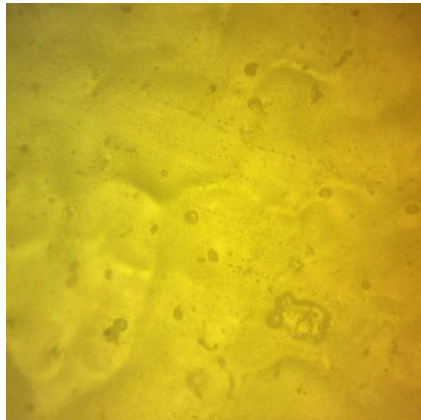
Type 2 – 25 %



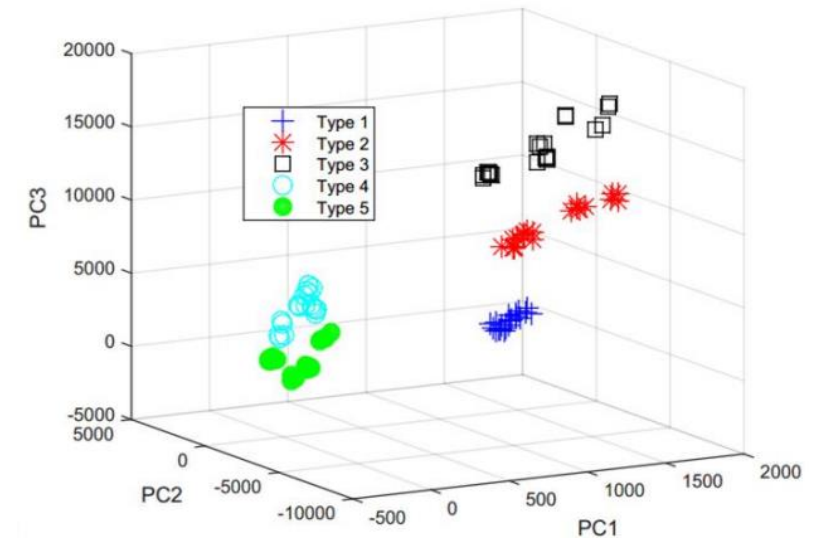
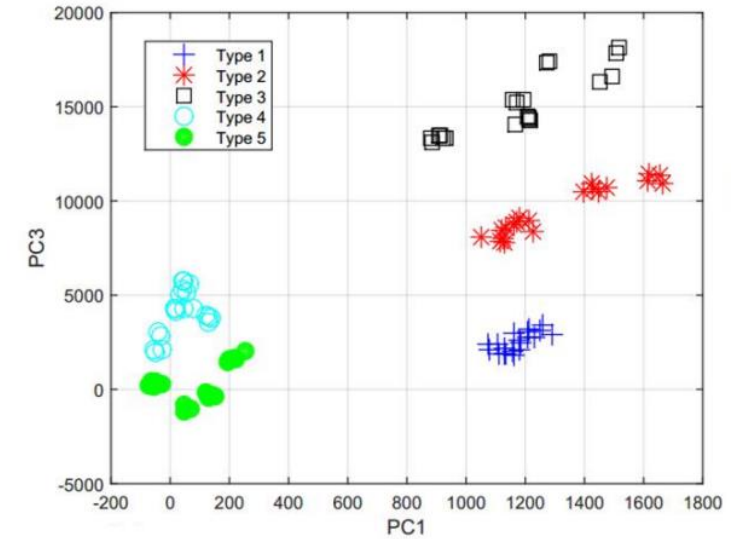
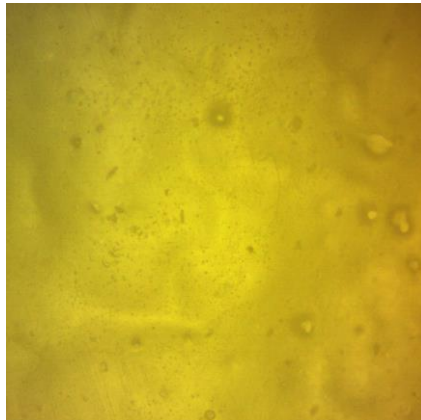
Type 3 – 50 %



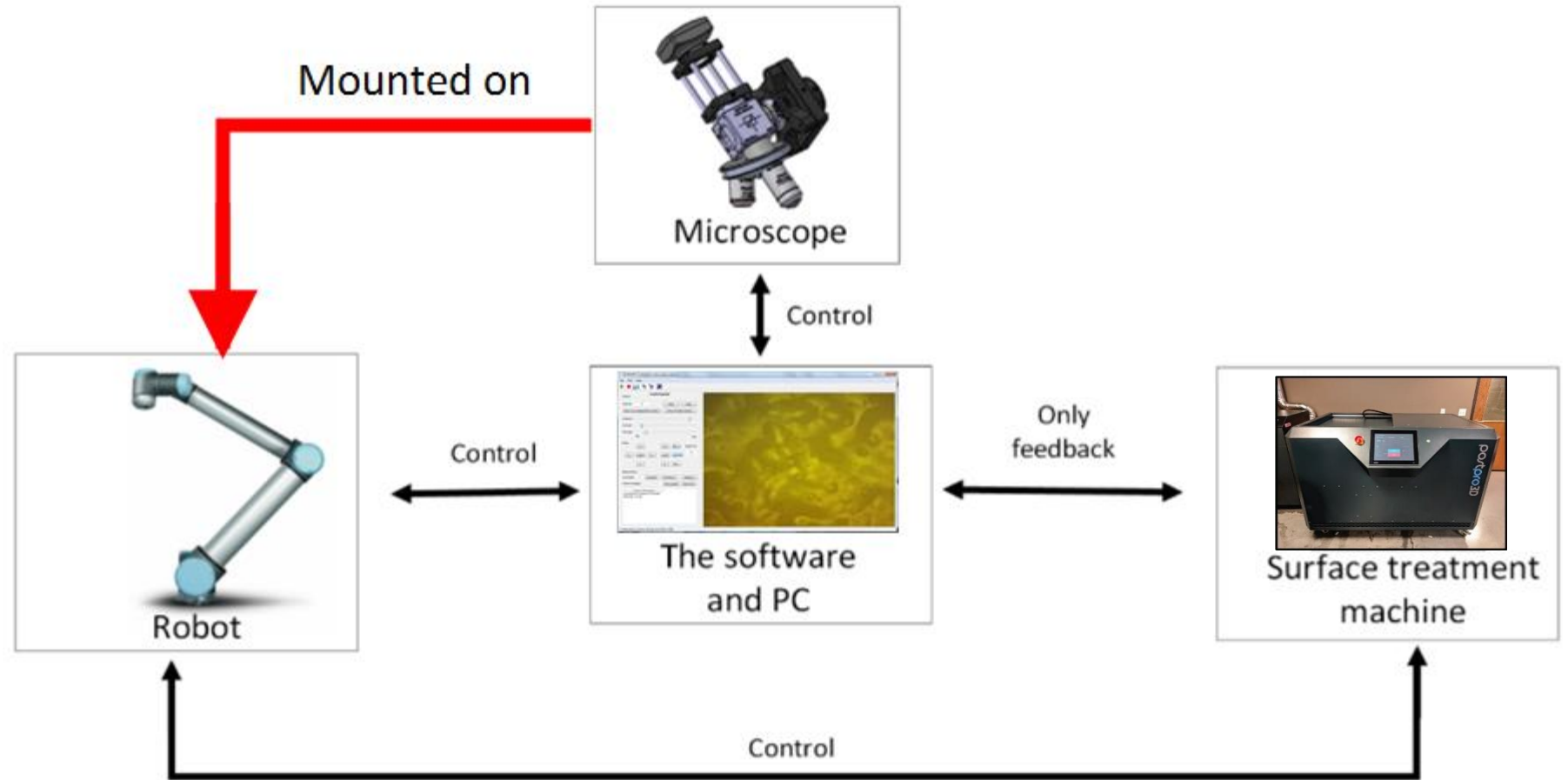
Type 4 – 75 %

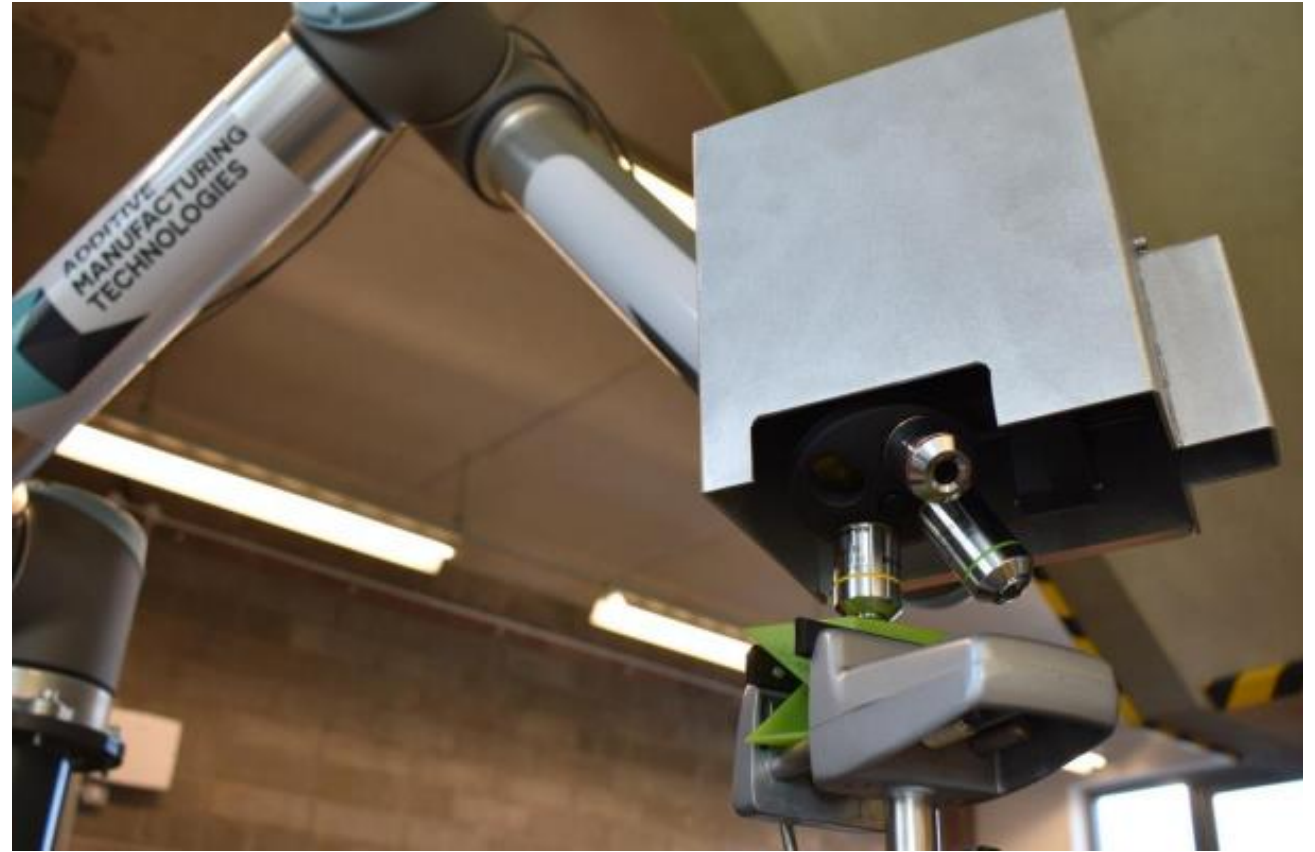
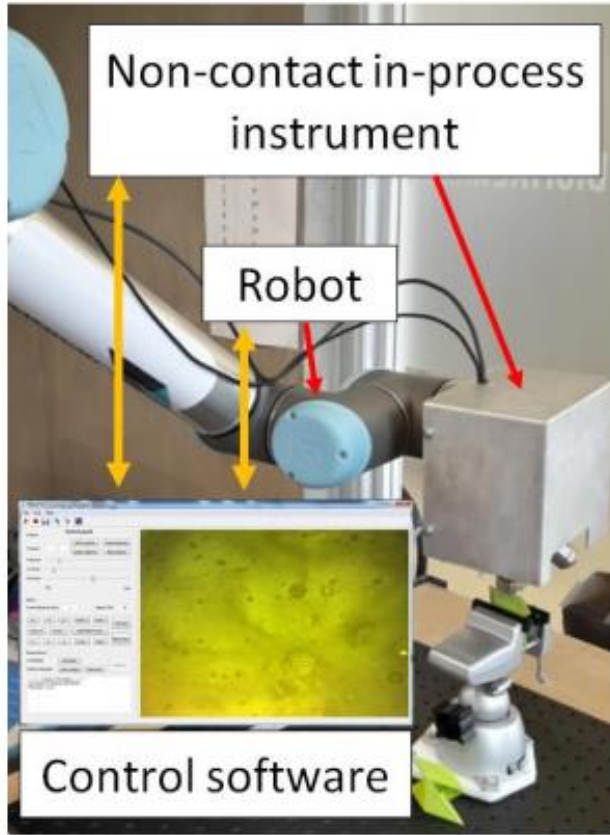


Type 5 – 100 %



- Instrument placement: in-line
- After the process, but still inside the process cycle



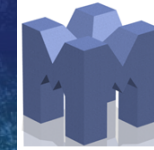


- Fundamental research to address the challenges for in-line measurements at millimetre-to micrometre-scale
- Exploitation of various state-of-the-art machine learning methods for improved measurement performance
- Implementation of the methodology for absolute in-line measurements, for example: diameter measurement, length, S_a , S_q , etc



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MANUFACTURING METROLOGY TEAM

Manufacturing Metrology Team at Nottingham



Thank you!



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